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Interpolation-Based Reconstructions for Raster-Scanned **Backscatter X-ray Radiography**



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Introduction

BACKGROUND

- The scanning radiography using a deep-penetrating megavoltage x-ray beam is widely used for screening cargo containers at ports and vehicles at borders, but this imaging technique is weak to discriminate low-Z materials, which are the basis of explosives and drugs
- Backscatter x-ray imaging (BXI), which utilizes image signal with the x-ray photons scattered back from the object, is known to be sensitive to low-Z materials
- The BXI is typically based on the raster scan, which may yield asymmetric, non-uniform sampling pitches along with horizontal and vertical directions; thus, without appropriate consideration for the raster scanning, the resulting images will suffer from geometric distortions

OBJECTIVES

- To formulate the raster-scanning trajectories considering the angular velocity of the collimator wheel and object speed, and to show the geometric distortions in scanned images
- To propose two simple synthetic algorithms of the raster-scan-sampled data, such as the distance-weighted average (WA) and the geometric interpolation (GI)



• Geometric distortion in the BXI is evaluated for a mesh phantom consisting of HDPE Raster-scan sampling is performed using the commercial MC code (MCNP version 5)

- BXI is performed for the Shepp-Logan phantom using MATLAB[®] 2020a
- Raster-scan sampling is performed using the Siddon's ray-tracing algorithm

Structural similarity index (SSIM)

SSIM(**x**, **y**) =
$$\frac{(2\mu_x\mu_y + c_1)(2\sigma_{xy} + c_2)}{(\mu_x^2 + \mu_y^2 + c_1)(\sigma_x^2 + \sigma_y^2 + c_2)}$$

$$H(\mathbf{x}) = -\sum_{n=1}^{N} p(x_n) \log[p(x_n)]$$

$$H(\mathbf{x}, \mathbf{y}) = -\sum_{n=1}^{N} \sum_{m=1}^{M} p(x_n, y_m) \log[p(x_n, y_m)]$$

$$I(\mathbf{x}, \mathbf{y}) = H(\mathbf{x}) + H(\mathbf{y}) - H(\mathbf{x}, \mathbf{y})$$

$$\text{NMI}_{\text{joint}} = \frac{I(\mathbf{x}, \mathbf{y})}{H(\mathbf{x}, \mathbf{y})}$$



Conclusion

- The conventional raster scanning for BXI can result in large distortions in synthetic images, depending on the mismatch between the ω and v_x
- The proposed synthesis methods restored reasonably the original image with some distortions around the relatively fine-sampling regions, even under the extreme raster-scanning conditions; thus they may also be used to accelerate the raster-scan procedure
- Our next study will include more quantitative evaluations of the proposed methods for a wide range of scan parameters, including phantom design

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